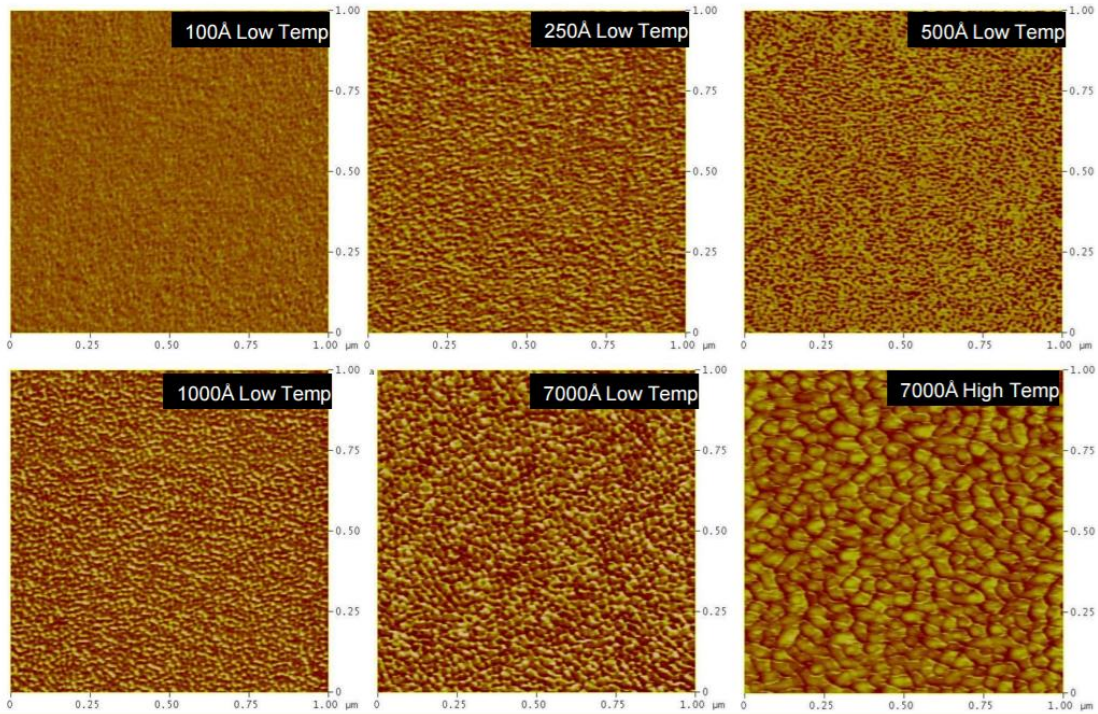
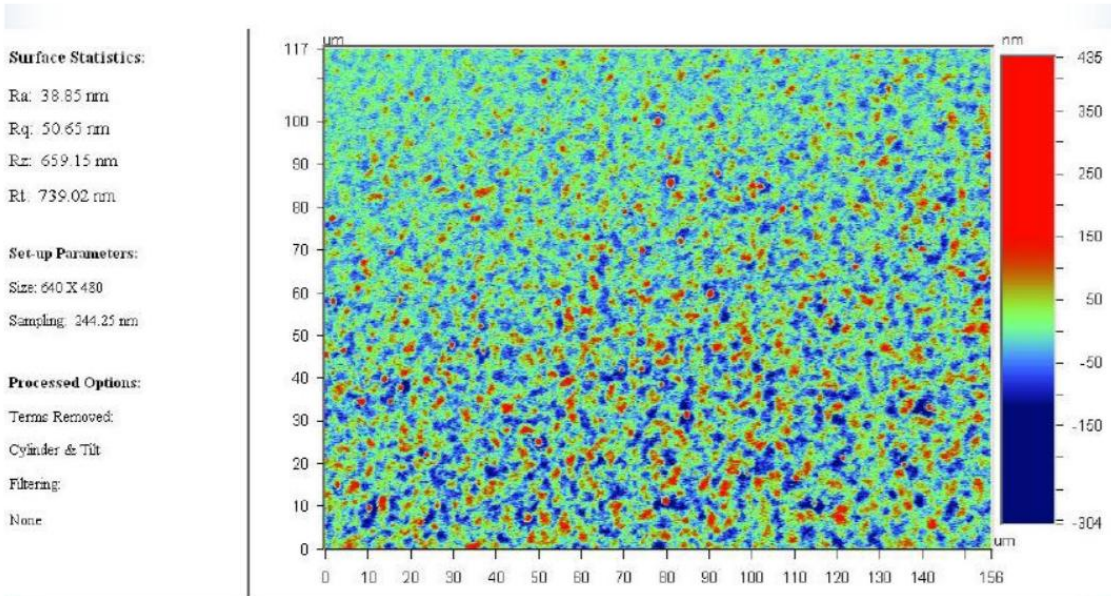


Roughness Data

Grain size via AFM

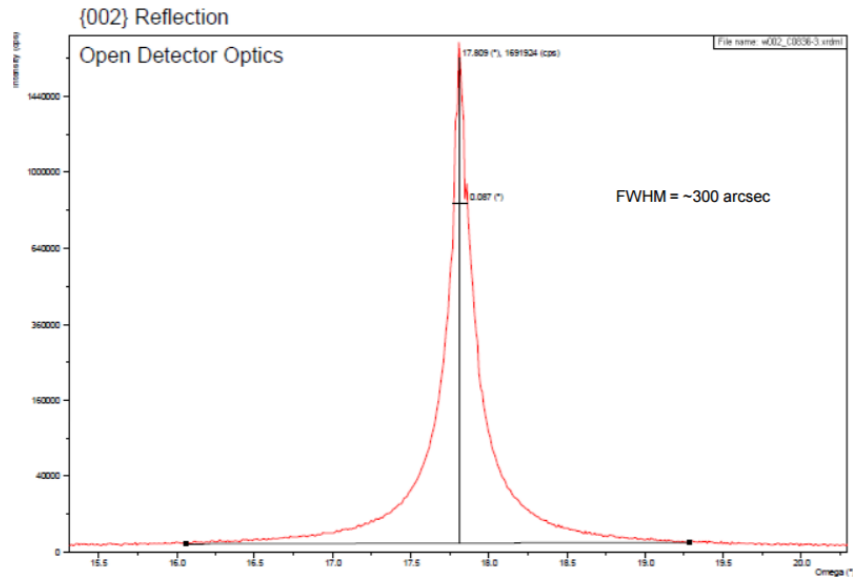


5 μm AlN on Sapphire via Wyko

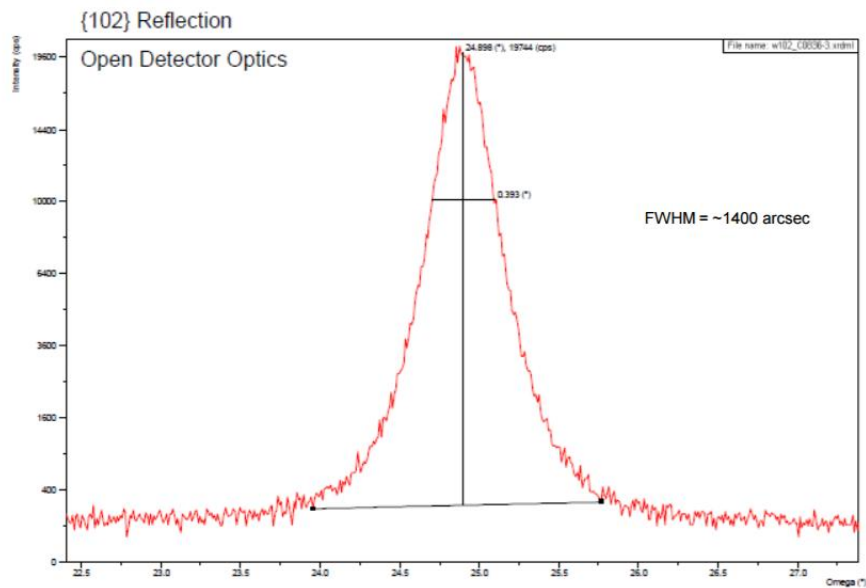


XRD Data

1 μ m AlN on Sapphire (002)

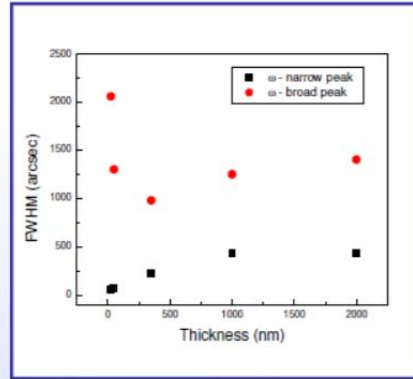
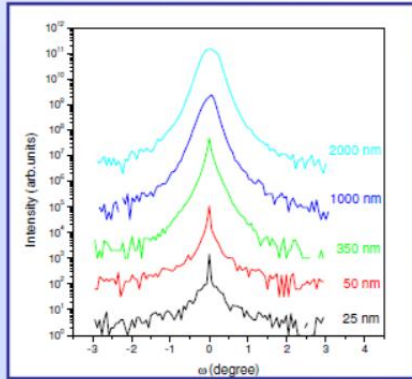


1 μ m AlN on Sapphire (102)



AlN films with varying thickness

- Structural characteristics by HRXRD analysis



- Models of the sublayer structures

